Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/749,076	MARTIN ET AL.
Examiner	Art Unit
Kim T. Huynh	2112

	SEAR	CHED	
Class	Subclass	Date	Examiner
710	301-304	3/16/2006	кн
710	100, 117	3/16/2006	КН
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INT	INTERFERENCE SEARCHED		
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SEARCH NO (INCLUDING SEARCH)
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	144 (1774) 114	